

Karel Hoffmann

List of Publications by Year in descending order

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Version: 2024-02-01

36
papers

163
citations

1937685

4
h-index

1372567

10
g-index

37
all docs

37
docs citations

37
times ranked

135
citing authors

#	ARTICLE	IF	CITATIONS
1	A simple method for extreme impedances measurement - experimental testing. , 2008, , .		28
2	A novel vector network analyzer. IEEE Transactions on Microwave Theory and Techniques, 1998, 46, 2520-2523.	4.6	21
3	Scalar Method for Reading of Chipless RFID Tags Based on Limited Ground Plane Backed Dipole Resonator Array. IEEE Transactions on Microwave Theory and Techniques, 2019, 67, 4547-4558.	4.6	20
4	Precise Measurement Using Coaxial-to-Microstrip Transition Through Radiation Suppression. IEEE Transactions on Microwave Theory and Techniques, 2013, 61, 2956-2965.	4.6	19
5	A Method for Direct Impedance Measurement in Microwave and Millimeter-Wave Bands. IEEE Transactions on Microwave Theory and Techniques, 2011, 59, 2123-2130.	4.6	17
6	Hidden problems in precise calibration on microstrip. , 2008, , .		8
7	Hidden problems in precise calibration on microstrip II explanation and solution. , 2011, , .		6
8	Radiation properties of coaxial-to-coplanar transitions in K band. Electronics Letters, 2012, 48, 1003-1004.	1.0	4
9	Six-Port Spatial Electromagnetic Wave Measurement. IEEE Transactions on Microwave Theory and Techniques, 2014, 62, 3161-3171.	4.6	4
10	General Method for Characterization of Power-Line EMI/RFI Filters Based on S-Parameter Evaluation. IEEE Transactions on Electromagnetic Compatibility, 2016, 58, 1465-1474.	2.2	4
11	Generalized method for broadband measurement of extreme impedances. , 2009, , .		3
12	Microwave interferometric method for metal sheet thickness measurement. , 2013, , .		3
13	Study of calibration standards for extreme impedances measurement. , 2014, , .		3
14	Calibration/verification standards for measurement of extremely high impedances. , 2015, , .		3
15	Generalized Approach for Phase Interferometric Measurements of Electromagnetic Field. Progress in Electromagnetics Research Symposium: [proceedings] Progress in Electromagnetics Research Symposium, 2007, 3, 1340-1345.	0.4	3
16	W-Band Imaging Sensor Using a Rectangular Waveguide Structure With Choke. IEEE Microwave and Wireless Components Letters, 2022, 32, 230-233.	3.2	3
17	A novel method for direct impedance measurement in microwave and mm-wave bands. , 2010, , .		2
18	Study of absorber materials usable on microstrip and their attribute improvements. , 2011, , .		2

#	ARTICLE	IF	CITATIONS
19	Investigation of Waveguide Sensors for Ultra-Short-Distance Measurements. , 2019, , .		2
20	Design of SMA 50 Ω Load Using 3D EM Field Simulator: Comparison with Reality. , 2008, , .		1
21	Calculation of maximal applicable gain for the generalized and the direct method for extreme impedances measurement. , 2010, , .		1
22	3D Modeling of assembly influence on packaged transistors. , 2011, , .		1
23	New multimode planar structure. , 2011, , .		1
24	Contactless distance measurement method. , 2011, , .		1
25	Precise microwave measurement of liquid level. , 2012, , .		1
26	Spatial vector measurement based on six-port concept. , 2013, , .		1
27	Novel Waveguide Sensors for Contactless Ultrashort-Distance Measurements. IEEE Transactions on Microwave Theory and Techniques, 2022, 70, 565-575.	4.6	1
28	Broadband Medium-Power Transistor Amplifier 12-18 GHz. , 2007, , .		0
29	Restrictions in Using Large Signal and Small Signal Models of FET Transistors. , 2007, , .		0
30	Parametric Equivalent Circuit of Single Layer Capacitor Mounted in Microstrip Line. , 2008, , .		0
31	Measurement of extreme impedances. , 2010, , .		0
32	A procedure for measurement of s-parameters and eye-diagram of backplane using two-port VNA. , 2012, , .		0
33	Transistor oscillator 24.7 GHz stabilized by HEM π mode of rectangular dielectric resonator. , 2013, , .		0
34	Novel Multimode Planar Absorbing Structure. IEEE Microwave and Wireless Components Letters, 2013, 23, 7-9.	3.2	0
35	Microstrip open π Problematic calibration standard. , 2015, , .		0
36	Traceable high impedance calibration standards. , 2016, , .		0